

# MOS FIELD EFFECT TRANSISTOR

# SWITCHING N-CHANNEL POWER MOS FET

#### DESCRIPTION

The NP161N04TUG is N-channel MOS Field Effect Transistor designed for high current switching applications.

#### ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE
NP161N04TUG-E1-AY Note			
NP161N04TUG-E2-AY <sup>Note</sup>	Pure Sn (Tin)	Tape 800 p/reel	TO-263-7pin (MP-25ZT) typ. 1.5 g

Note Pb-free (This product does not contain Pb in the external electrode).

#### **FEATURES**

• Super low on-state resistance

 $R_{DS(on)}$  = 1.35 m $\Omega$  TYP. / 1.8 m $\Omega$  MAX. (VGS = 10 V, ID = 80 A)

High Current Rating

 $I_{D(DC)}$  = ±160 A

#### ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	40	V
Gate to Source Voltage (VDs = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	ID(DC)	±160	А
Drain Current (pulse) <sup>Note1</sup>	D(pulse)	±640	А
Total Power Dissipation (Tc = 25°C)	Pt1	250	W
Total Power Dissipation (T <sub>A</sub> = 25°C)	Pt2	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Repetitive Avalanche Current Note2	lar	70	А
Repetitive Avalanche Energy Note2	Ear	650	mJ

**Notes 1.** PW  $\leq$  10  $\mu$ s, Duty Cycle  $\leq$  1%

**2.** T<sub>ch</sub> = 150°C, V<sub>DD</sub> = 25 V, R<sub>G</sub> = 25  $\Omega$ , V<sub>GS</sub> = 20  $\rightarrow$  0 V, L = 100  $\mu$ H

#### THERMAL RESISTANCE

Channel to Case Thermal Resistance	Rth(ch-C)	0.6	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V			1	μA
Gate Leakage Current	lgss	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> = 0 V			±100	nA
Gate to Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	3.0	4.0	V
Forward Transfer Admittance Note	y <sub>fs</sub>	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 40 A	35	88		S
Drain to Source On-state Resistance Note	RDS(on)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 80 A		1.35	1.8	mΩ
Input Capacitance	Ciss	V <sub>DS</sub> = 25 V,		13500	20250	pF
Output Capacitance	Coss	V <sub>GS</sub> = 0 V,		1200	1800	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		750	1350	pF
Turn-on Delay Time	td(on)	V <sub>DD</sub> = 20 V, I <sub>D</sub> = 80 A,		50	110	ns
Rise Time	tr	V <sub>GS</sub> = 10 V,		40	100	ns
Turn-off Delay Time	td(off)	R <sub>G</sub> = 0 Ω		110	220	ns
Fall Time	tr			20	40	ns
Total Gate Charge	QG	V <sub>DD</sub> = 32 V,		230	345	nC
Gate to Source Charge	QGS	V <sub>GS</sub> = 10 V,		50		nC
Gate to Drain Charge	Qgd	I <sub>D</sub> = 160 A		75		nC
Body Diode Forward Voltage Note	VF(S-D)	I⊧ = 160 A, V <sub>GS</sub> = 0 V		0.9	1.5	V
Reverse Recovery Time	trr	I⊧ = 160 A, V <sub>GS</sub> = 0 V,		60		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ <i>µ</i> s		100		nC

# ELECTRICAL CHARACTERISTICS (TA = 25°C)

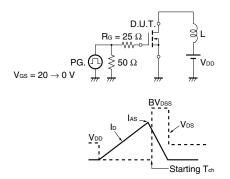
Note Pulsed test

#### TEST CIRCUIT 1 AVALANCHE CAPABILITY

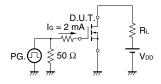
#### TEST CIRCUIT 2 SWITCHING TIME

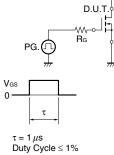
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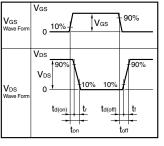
 $V_{\text{DD}}$ 



#### TEST CIRCUIT 3 GATE CHARGE

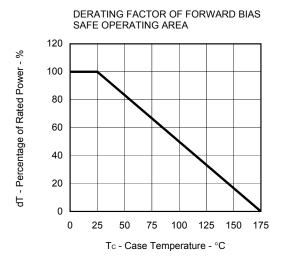


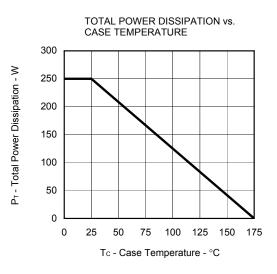




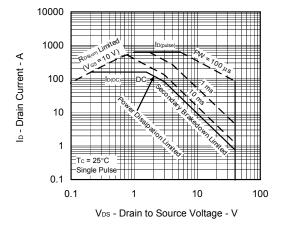
2

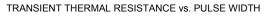
## TYPICAL CHARACTERISTICS (TA = 25°C)

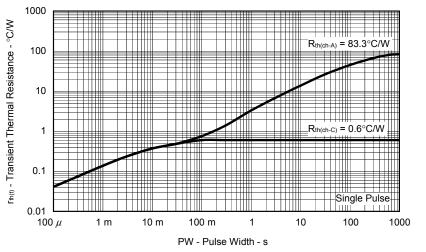




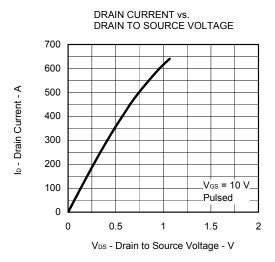




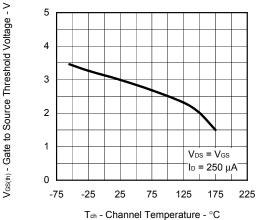


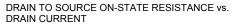


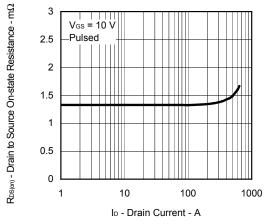
Data Sheet D19411EJ1V0DS



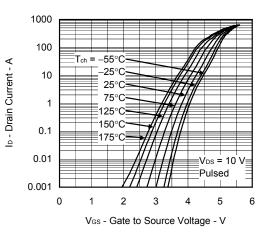




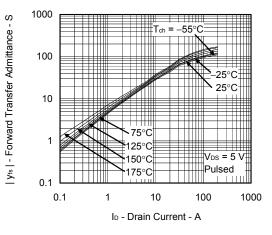


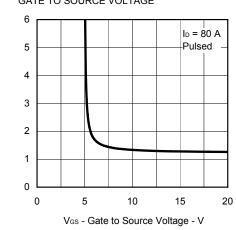


FORWARD TRANSFER CHARACTERISTICS



FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT





DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

Data Sheet D19411EJ1V0DS

 $R_{DS(on)}$  - Drain to Source On-state Resistance -  $m\Omega$ 

4

100

12

9

6

3

0

250

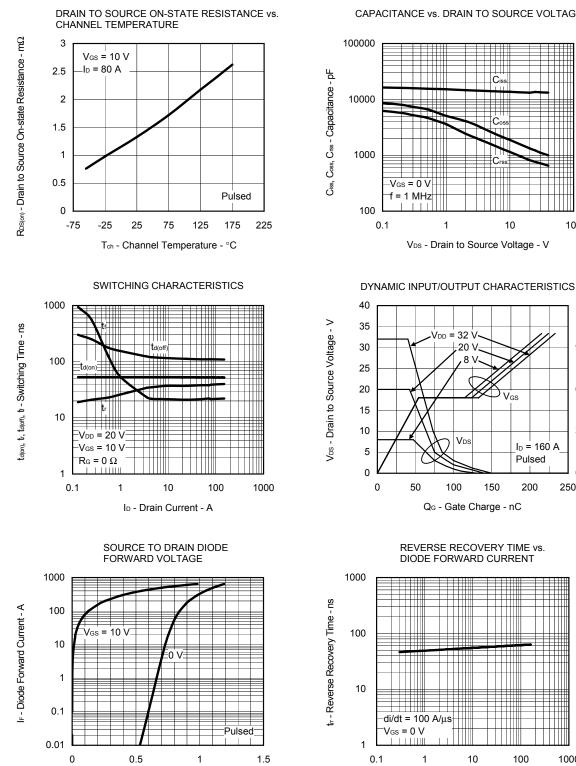
1000

5

Gate to Source Voltage - V

V<sub>GS</sub> -





IF - Diode Forward Current - A

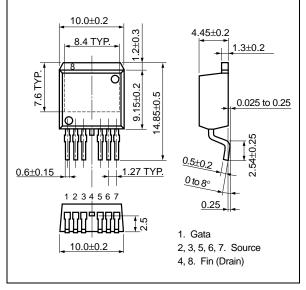
V<sub>F(S-D)</sub> - Source to Drain Voltage - V

Data Sheet D19411EJ1V0DS

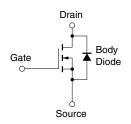
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

## PACKAGE DRAWING (Unit: mm)

#### TO-263-7pin (MP-25ZT)



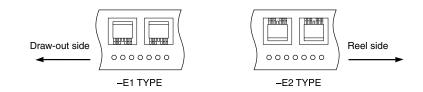
#### EQUIVALENT CIRCUIT



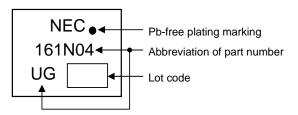
**Remark** Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

#### TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



#### MARKING INFORMATION



#### **RECOMMENDED SOLDERING CONDITIONS**

The NP161N04TUG should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol	
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below		
	Time at maximum temperature: 10 seconds or less		
	Time of temperature higher than 220°C: 60 seconds or less	IR60-00-3	
	Preheating time at 160 to 180°C: 60 to 120 seconds		
	Maximum number of reflow processes: 3 times		
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less		
Partial heating	Maximum temperature (Pin temperature): 350°C or below		
	Time (per side of the device): 3 seconds or less	P350	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		

Caution Do not use different soldering methods together (except for partial heating).

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